# **IGBT - Field Stop, Trench**

1000 V, 40 A

# FGH40T100SMD, FGH40T100SMD-F155

#### Description

Using innovative field stop trench IGBT technology, ON Semiconductor's new series of field stop trench IGBTs offer the optimum performance for hard switching application such as solar inverter, UPS, welder and PFC applications.

#### **Features**

- High Current Capability
- Low Saturation Voltage:  $V_{CE(sat)} = 1.9 \text{ V(Typ.)}$  @  $I_C = 40 \text{ A}$
- High Input Impedance
- Fast Switching
- These Devices are Pb-Free and are RoHS Compliant

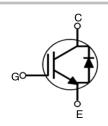
#### **Applications**

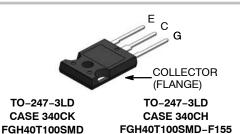
• UPS, Welder, PFC



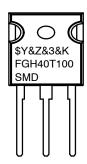
#### ON Semiconductor®

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#### MARKING DIAGRAM



= ON Semiconductor Logo \$Y = Assembly Plant Code &Z &3 = Numeric Date Code = Lot Code FGH40T100SMD = Specific Device Code

#### **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 2 of this data sheet.

1

## **ABSOLUTE MAXIMUM RATINGS** ( $T_C = 25^{\circ}C$ unless otherwise noted)

Description		Symbol	Ratings	Unit
Collector to Emitter Voltage		V <sub>CES</sub>	1000	V
Gate to Emitter Voltage		$V_{GES}$	±25	V
Transient Gate to Emitter Voltage		1	±30	V
Collector Current	T <sub>C</sub> = 25°C	I <sub>C</sub>	80	А
Collector Current	T <sub>C</sub> = 100°C	1	40	А
Pulsed Collector Current (Note 1)	T <sub>C</sub> = 25°C	I <sub>CM</sub>	120	А
Diode Forward Current	T <sub>C</sub> = 25°C	I <sub>F</sub>	80	А
Diode Forward Current	T <sub>C</sub> = 100°C	1	40	Α
Pulsed Diode Forward Current (Note 1)	T <sub>C</sub> = 25°C	I <sub>FM</sub>	120	А
Maximum Power Dissipation	T <sub>C</sub> = 25°C	$P_{D}$	333	W
Maximum Power Dissipation	T <sub>C</sub> = 100°C	1 1	166	W
Operating Junction Temperature		TJ	-55 to +175	°C
Storage Temperature Range		T <sub>stg</sub>	-55 to +175	°C
Maximum Lead Temp. for Soldering Purpos	es, 1/8" from Case for 5 Seconds	TL	300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Repetitive Rating: Pulse width limited by max. junction temperature.

## THERMAL CHARACTERISTICS

Parameter	Symbol	Тур	Max	Unit
Thermal Resistance, Junction to Case (IGBT)	$R_{ heta JC}$	-	0.45	°C/W
Thermal Resistance, Junction to Case (Diode)	$R_{ heta JC}$	-	0.8	°C/W
Thermal Resistance, Junction to Ambient	$R_{ heta JA}$	-	40	°C/W

#### PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FGH40T100SMD	FGH40T100SMD	TO-247-3	-	-	30
FGH40T100SMD	FGH40T100SMD-F155	TO-247-3	-	-	30

## **ELECTRICAL CHARACTERISTICS OF THE IGBT** (T<sub>C</sub> = 25°C unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
OFF CHARACTERISTICS	-					
Collector to Emitter Breakdown Voltage	BV <sub>CES</sub>	$V_{GE} = 0 \text{ V}, I_{C} = 1 \text{ mA}$	1000	-	-	V
Temperature Coefficient of Breakdown Voltage	$\Delta BV_{CES}/\Delta T_{J}$	$V_{GE}$ = 0 V, $I_{C}$ = 250 $\mu A$		0.6		V/°C
Collector Cut-Off Current	I <sub>CES</sub>	V <sub>CE</sub> = V <sub>CES</sub> , V <sub>GE</sub> = 0 V	-	-	1000	μΑ
G-E Leakage Current	I <sub>GES</sub>	V <sub>GE</sub> = V <sub>GES</sub> , V <sub>CE</sub> = 0 V	-	_	±500	nA
ON CHARACTERISTICS						
G-E Threshold Voltage	V <sub>GE(th)</sub>	$I_C = 250 \mu A, V_{CE} = V_{GE}$	4.2	5.3	6.5	V
Collector to Emitter Saturation Voltage	V <sub>CE(sat)</sub>	I <sub>C</sub> = 40 A, V <sub>GE</sub> = 15 V	-	1.9	2.3	V
		I <sub>C</sub> = 40 A, V <sub>GE</sub> = 15 V, T <sub>C</sub> = 175°C	-	2.4	-	V

# **ELECTRICAL CHARACTERISTICS OF THE IGBT** ( $T_C = 25^{\circ}C$ unless otherwise noted) (continued)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
DYNAMIC CHARACTERISTICS						
Input Capacitance	C <sub>ies</sub>	$V_{CE} = 30 \text{ V}, V_{GE} = 0 \text{ V}, f = 1 \text{ MHz}$	_	3980	5295	pF
Output Capacitance	C <sub>oes</sub>		-	124	165	pF
Reverse Transfer Capacitance	C <sub>res</sub>		-	76	115	pF
SWITCHING CHARACTERISTICS						
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>CC</sub> = 600 V, I <sub>C</sub> = 40 A,	_	29	38	ns
Rise Time	t <sub>r</sub>	R <sub>G</sub> = 10 Ω, V <sub>GE</sub> = 15 V, Inductive Load, T <sub>C</sub> = 25°C	_	42	55	ns
Turn-Off Delay Time	t <sub>d(off)</sub>		_	285	371	ns
Fall Time	t <sub>f</sub>		_	23	30	ns
Turn-On Switching Loss	E <sub>on</sub>		_	2.35	3.1	mJ
Turn-Off Switching Loss	E <sub>off</sub>		-	1.15	1.5	mJ
Total Switching Loss	E <sub>ts</sub>		-	3.5	4.6	mJ
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>CC</sub> = 600 V, I <sub>C</sub> = 40 A,	-	27	36	ns
Rise Time	t <sub>r</sub>	$R_G = 10 \Omega$ , $V_{GE} = 15 V$ , Inductive Load, $T_C = 175^{\circ}C$	-	49	64	ns
Turn-Off Delay Time	t <sub>d(off)</sub>		-	285	371	ns
Fall Time	t <sub>f</sub>		-	20	26	ns
Turn-On Switching Loss	E <sub>on</sub>		_	4.4	5.7	mJ
Turn-Off Switching Loss	E <sub>off</sub>		-	1.9	2.5	mJ
Total Switching Loss	E <sub>ts</sub>		_	6.3	8.2	mJ
Total Gate Charge	Qg	V <sub>CE</sub> = 600 V, I <sub>C</sub> = 40 A, V <sub>GE</sub> = 15 V	-	265	398	nC
Gate to Emitter Charge	Q <sub>ge</sub>	7	-	32	48	nC
Gate to Collector Charge	Q <sub>gc</sub>	7	_	135	203	nC

## **ELECTRICAL CHARACTERISTICS OF THE DIODE** (T<sub>J</sub> = 25°C unless otherwise noted)

Parametr	Symbol	Test Conditi	ons	Min	Тур	Max	Unit
Diode Forward Voltage	V <sub>FM</sub>	I <sub>F</sub> = 40 A	T <sub>C</sub> = 25°C	_	3.4	4.4	V
			T <sub>C</sub> = 175°C	-	2.6	-	
Diode Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 40 A,	T <sub>C</sub> = 25°C	-	60	78	ns
		dI <sub>F</sub> /dt = 200 A/μs	T <sub>C</sub> = 175°C	-	256	-	
Diode Reverse Recovery Charge	Q <sub>rr</sub>		T <sub>C</sub> = 25°C	_	185	260	nC
			T <sub>C</sub> = 175°C	_	1512	_	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

#### TYPICAL PERFORMANCE CHARACTERISTICS

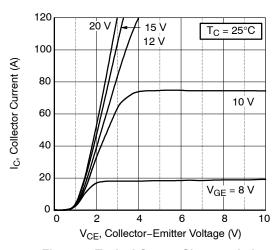


Figure 1. Typical Output Characteristics

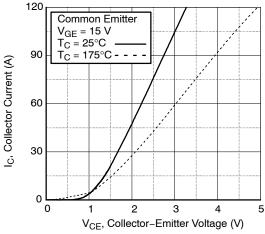


Figure 3. Typical Saturation Voltage Characteristics

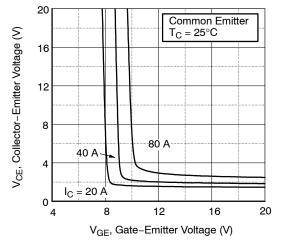


Figure 5. Saturation Voltage vs V<sub>GE</sub>

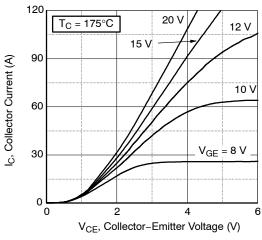


Figure 2. Typical Output Characteristics

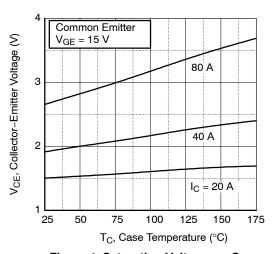


Figure 4. Saturation Voltage vs. Case Temperature at Variant Current Level

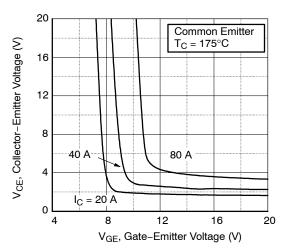


Figure 6. Saturation Voltage vs V<sub>GE</sub>

#### TYPICAL PERFORMANCE CHARACTERISTICS (continued)

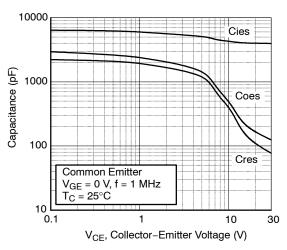


Figure 7. Capacitance Characteristics

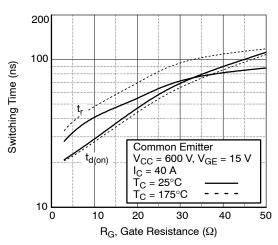


Figure 9. Turn-On Characteristics vs. Gate Resistance

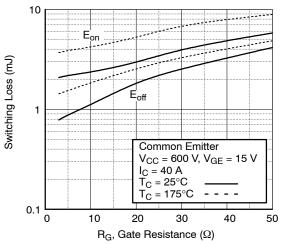


Figure 11. Switching Loss vs. Gate Resistance

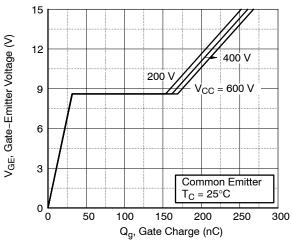


Figure 8. Gate Charge Characteristics

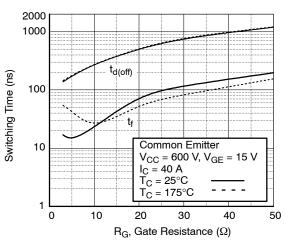


Figure 10. Turn-Off Characteristics vs. Gate Resistance

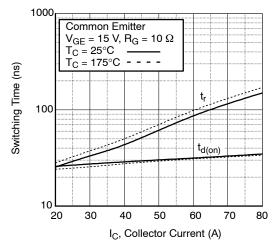


Figure 12. Turn-On Characteristics vs. Collector Current

# TYPICAL PERFORMANCE CHARACTERISTICS (continued)

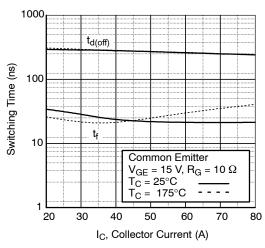


Figure 13. Turn-Off Characteristics vs. Collector Current

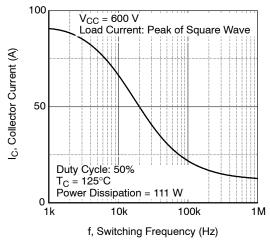


Figure 15. Load Current vs. Frequency

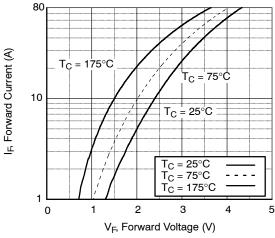


Figure 17. Forward Characteristics

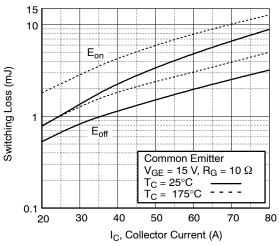


Figure 14. Switching Loss vs. Collector Current

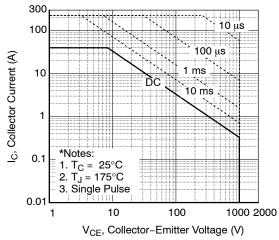


Figure 16. SOA Characteristics

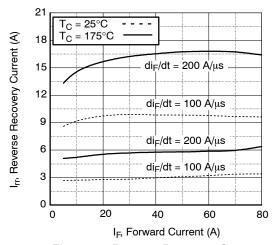


Figure 18. Reverse Recovery Current

#### TYPICAL PERFORMANCE CHARACTERISTICS (continued)

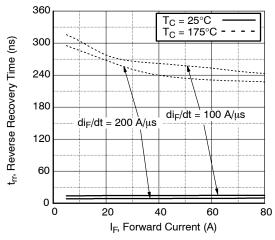


Figure 19. Reverse Recovery Time

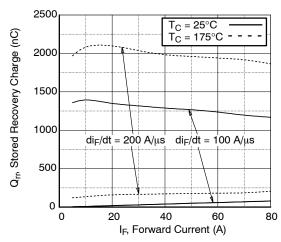


Figure 20. Stored Charge

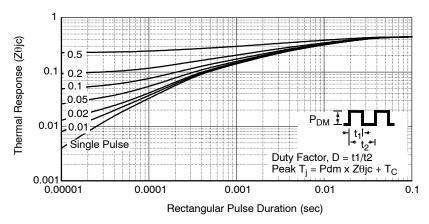


Figure 21. Transient Thermal Impedance of IGBT

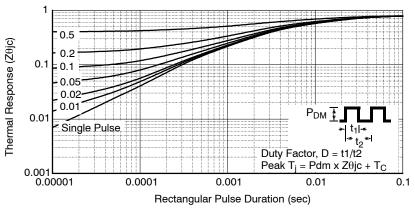
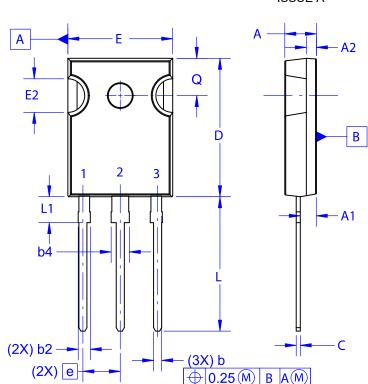


Figure 22. Transient Thermal Impedance of Diode

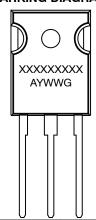
#### TO-247-3LD CASE 340CH **ISSUE A**





- A. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- B. ALL DIMENSIONS ARE IN MILLIMETERS.
- C. DRAWING CONFORMS TO ASME Y14.5 2009.
  D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1.
- E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.

# GENERIC **MARKING DIAGRAM\***



XXXX = Specific Device Code

= Assembly Location

WW = Work Week

= Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

	DATE (	09 OCT 2019
Ø P —		P1 D2
S E1 —	2	D1
		<u>J</u>

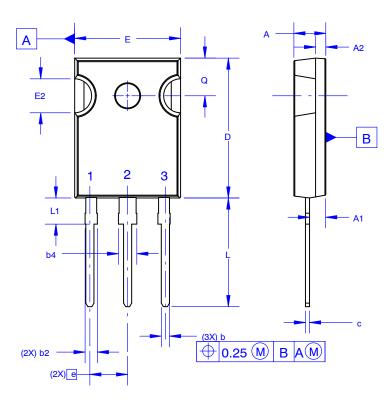
DIM	MIL	LIMETER	S
DIM	MIN	NOM	MAX
Α	4.58	4.70	4.82
<b>A</b> 1	2.29	2.475	2.66
A2	1.40	1.50	1.60
D	20.32	20.57	20.82
Е	15.37	15.62	15.87
E2	4.96	5.08	5.20
е	~	5.56	~
L	19.75	20.00	20.25
L1	3.69	3.81	3.93
ØΡ	3.51	3.58	3.65
Q	5.34	5.46	5.58
S	5.34	5.46	5.58
b	1.17	1.26	1.35
b2	1.53	1.65	1.77
b4	2.42	2.54	2.66
С	0.51	0.61	0.71
D1	13.08	~	~
D2	0.51	0.93	1.35
E1	12.81	~	~
ØP1	6.61	6.73	6.85

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#### TO-247-3LD SHORT LEAD

CASE 340CK ISSUE A





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# GENERIC MARKING DIAGRAM\*



XXXX = Specific Device Code

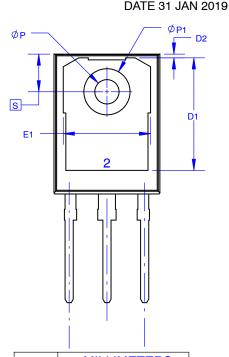
A = Assembly Location

Y = Year

WW = Work Week

ZZ = Assembly Lot Code

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.



DIM	MIL	LIMET	ERS
DIIVI	MIN	NOM	MAX
Α	4.58	4.70	4.82
<b>A</b> 1	2.20	2.40	2.60
A2	1.40	1.50	1.60
b	1.17	1.26	1.35
b2	1.53	1.65	1.77
b4	2.42	2.54	2.66
С	0.51	0.61	0.71
D	20.32	20.57	20.82
D1	13.08	~	~
D2	0.51	0.93	1.35
E	15.37	15.62	15.87
E1	12.81	?	~
E2	4.96	5.08	5.20
е	~	5.56	~
L	15.75	16.00	16.25
L1	3.69	3.81	3.93
ØΡ	3.51	3.58	3.65
ØP1	6.60	6.80	7.00
Q	5.34	5.46	5.58
S	5.34	5.46	5.58

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